

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/061,179	AUWENS ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
TAN X. DINH	2627	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Interference Search History Printout		10/13/2006	T.D